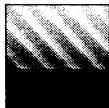


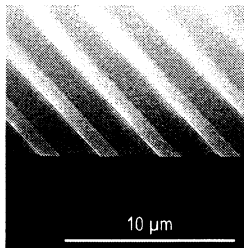
ULTRASHARP
CANTILEVERS & GRATINGS

TGZ03

[test structure]



TGZ03



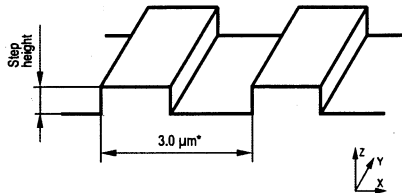
SEM image of one of the silicon gratings of TGZ Series.

Grating Characteristics:

Active area: **3x3 mm**

Step height: **493 nm**

Accuracy: **6 nm**



* given for information only

Silicon calibration gratings of the TGZ series comprise a one-dimensional array of rectangular steps with a calibrated height value. The gratings are intended for Z-axis calibration of SPM scanners.